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650 Route des Lucioles
F-06921 Sophia Antipolis Cedex - FRANCE

Tel.: +33 4 92 94 42 00 Fax: +33 4 93 65 47 16

Siret N° 348 623 562 00017 - NAF 742 C
Association à but non lucratif enregistrée à la
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Foreword

This Technical Specification (TS) has been produced by the 3rd Generation Partnership Project (3GPP).

The contents of the present document are subject to continuing work within the TSG and may change following formal TSG approval. Should the TSG modify the contents of the present document, it will be re-released by the TSG with an identifying change of release date and an increase in version number as follows:

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- x the first digit:
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1 Scope

The present document specifies the Radio Frequency (RF) test methods and conformance requirements for UTRA Base Stations (BS) operating in the TDD mode. These have been derived from, and are consistent with, the UTRA base station (BS) specifications defined in 3GPP TS 25.105 [1]. The document covers all three options of the TDD mode, which are the 3,84 Mcps (incorporating MBSFN IMB), the 1,28 Mcps and the 7.68 Mcps options respectively. The requirements are listed in different subsections only if the parameters deviate.

In this TS, the reference point for RF connections (except for the measurement of mean transmitted RF carrier power) is the antenna connector, as defined by the manufacturer. This TS does not apply to repeaters or RF devices which may be connected to an antenna connector of a BS.

2 References

The following documents contain provisions which, through reference in this text, constitute provisions of the present document.

- References are either specific (identified by date of publication, edition number, version number, etc.) or non-specific.
- For a specific reference, subsequent revisions do not apply.
- For a non-specific reference, the latest version applies. In the case of a reference to a 3GPP document (including a GSM document), a non-specific reference implicitly refers to the latest version of that document in the same Release as the present document.

- [1] 3GPP TS 25.105: "UTRA (BS) TDD: Radio transmission and reception".
- [2] IEC 60721-3-3 (1994): "Classification of environmental conditions - Part 3: Classification of groups of environmental parameters and their severities - Section 3: Stationary use at weather protected locations".
- [3] IEC 60721-3-4 (1995): "Classification of environmental conditions - Part 3: Classification of groups of environmental parameters and their severities - Section 4: Stationary use at non-weather protected locations".
- [4] IEC 60068-2-1 (1990): "Environmental testing - Part 2: Tests. Tests A: Cold".
- [5] ETR 028: "Uncertainties in the measurement of mobile radio equipment characteristics".
- [6] Recommendation ITU-R SM.329: "Unwanted emissions in the spurious domain".
- [7] Recommendation ITU-R SM.328: "Spectra and bandwidth of emissions".
- [8] IEC 60068-2-6 (1995): "Environmental testing - Part 2: Tests - Test Fc: Vibration (sinusoidal)".
- [9] 3GPP TR 25.942: "RF System Scenarios".
- [10] ITU-T recommendation O.153: "Basic parameters for the measurement of error performance at bit rates below the primary rate".
- [11] 3GPP TS 36.104: "Evolved Universal Terrestrial Radio Access (E-UTRA); Base Station (BS) radio transmission and reception".
- [12] 3GPP TS 37.141: "E-UTRA, UTRA and GSM/EDGE; Multi-Standard Radio (MSR) Base Station (BS) conformance testing".
- [13] ITU-R Recommendation M.1545, "Measurement uncertainty as it applies to test limits for the terrestrial component of International Mobile Telecommunications-2000".